

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of

GLASPER et al

Serial No. 10/520,850

Filed: January 11, 2005



Atty. Ref.: 124-1101

TC/A.U.: 2878

Examiner: T. Ko

For: PHOTODETECTOR CIRCUITS

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December 27, 2006

Commissioner for Patents

P.O. Box 1450

Alexandria, VA 22313-1450

Sir:

INFORMATION DISCLOSURE STATEMENT

As suggested by 37 C.F.R. 1.97, the undersigned attorney brings to the attention of the Patent and Trademark Office the references listed on the attached form PTO-1449.

- ☐ All listed documents are attached.
- ☒ Copies of U.S. Patent Publications are not required and are not attached.
- ☒ Listed foreign patent publications and other documents are enclosed.
- ☐ The listed documents were cited in the ISR and copies should have been

supplied by WIPO directly to the US PTO. If copies are not timely received from WIPO, please telephone the undersigned so that copies can be timely supplied for the Examiner's consideration in this US National Phase Application.

This is not to be construed as a representation that a search has been made or that no better prior art exists, or that a reference is relevant merely because cited.

The Examiner is requested to initial the attached form PTO/SB/08a and to return a copy of the initialed document to the undersigned as an indication that the attached references have been considered and made of record.

Pursuant to Rule 37 C.F.R. §1.97(c), a fee of \$180.00 as specified in Rule 17(p) is attached. If there is any shortage in the fee, please charge the deposit account of Nixon & Vanderhye, Account No. 14-1140.

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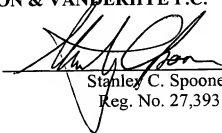
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Respectfully submitted,

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**INFORMATION DISCLOSURE
CITATION**

ATTY. DOCKET NO.

SERIAL NO.

124-1101

10/520,850

APPLICANT

GLASPER et al

(Use several sheets if necessary)

FILING DATE

GROUP

January 11, 2005

2878

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
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2 202 624	9/1988	GB			
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OTHER DOCUMENTS (including Author, Title, Date, Pertinent pages, etc.)

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Jackson et al Proc. IEEE 2001 Int. Conference on Microelectronic Test Structures, Vol. 14, March 2001 pp. 165-170 Process Monitoring and Defect Characterization of Single Photon Avalanche Diodes

*Examiner

Date Considered

Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Initial this form with next communication to application.